

From the Editor

2017 *Microscopy Today* Innovation Awards

Congratulations to the winners of the eighth annual *Microscopy Today* Innovation Awards competition. These awards honor innovative microscopy-related products and methods that appeared in the previous year.

Our team of judges, led by Tom Kelly, looked for innovations that will make new scientific investigations possible. The ten winning innovations were selected on the basis of their importance and usefulness to the microscopy community. The entries most likely to win are those that provide better or entirely new methods of analysis using some type of microscope or microanalytical instrument.

The 2017 *Microscopy Today* Innovation Award winners are:

Aalto University (Finland) for the black-silicon induced-junction silicon photodiode
Bruker-Hysitron for NanoScratch *in-situ* nanomechanical testing in the SEM
Keyence Corporation of America for the VR-3000 non-contact wide-area 3D measurement system
University of Missouri for the plasmonic grating platform to replace glass slides
University of Newcastle (Australia) for the scanning helium atom microscope
Oak Ridge National Laboratory and the University of Uppsala (Sweden) for a STEM method to observe magnetic ordering with atomic resolution
Phasefocus for the Liveocyte[®] Kinetic Cytometer to analyze live cell populations
Scripps Institution of Oceanography for the benthic underwater microscope
University of Washington and Shenzhen Institutes of Advanced Technology for scanning thermo-ionic microscopy
Yale University for multimodal imaging using a coherence switching laser

Descriptions of the above innovations are given in an article within this issue. Nomination applications for the next competition are available upon request (charles.lyman@lehigh.edu). The deadline for the next competition is March 21, 2018.

Charles Lyman
Editor-in-Chief

Publication Objective: to provide information of interest to microscopists.

Microscopy Today is a controlled-circulation trade magazine owned by the Microscopy Society of America that is published six times a year in the odd months. Editorial coverage spans all microscopy techniques including light microscopy, scanning probe microscopy, electron microscopy, ion-beam techniques, and the wide range of microanalytical methods. Readers and authors come from both the life sciences and the physical sciences. The typical length of an article is about 2,000 words plus figures and tables; feature articles are longer. Interested authors should consult "Instructions for Contributors" on the *Microscopy Today* website: www.microscopy-today.com.

ISSN 1551-9295

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Magazine website:

<http://www.microscopy-today.com>
Free subscriptions are available

Publisher

Cambridge University Press
One Liberty Plaza, 20th Floor
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Circulation: 18,000

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